N-Channel Shielded Gate POWERTRENCH® MOSFET

100 V, 268 A, 1.7 mΩ

Description

This N-Channel MOSFET is produced using ON Semiconductor's advanced POWERTRENCH process that incorporates Shielded Gate technology. This process has been optimized to minimize on-state resistance and yet maintain superior switching performance with best in class soft body diode.

Features

- Max $R_{DS(on)} = 1.75 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 100 \text{ A}$
- Max $R_{DS(on)} = 1.7 \text{ m}\Omega$ at $V_{GS} = 12 \text{ V}$, $I_D = 100 \text{ A}$
- Max $R_{DS(on)} = 1.65 \text{ m}\Omega$ at $V_{GS} = 15 \text{ V}$, $I_D = 100 \text{ A}$
- Max $R_{DS(on)} = 4.4 \text{ m}\Omega$ at $V_{GS} = 6 \text{ V}$, $I_D = 63 \text{ A}$
- 50% Lower Qrr than Other MOSFET Suppliers
- Lowers Switching Noise/EMI
- MSL1 Robust Package Design
- 100% UIL Tested

Applications

- Industrial Motor Drive
- Industrial Power Supply
- Industrial Automation
- Battery Operated Tools
- Battery Protection
- Solar Inverters
- UPS and Energy Inverters
- Energy Storage
- Load Switch

MAXIMUM RATINGS (T_C = 25°C, Unless otherwise specified)

Symbol	Parameter	Ratings	Unit
V _{DS}	Drain to Source Voltage	100	V
V _{GS}	Gate to Source Voltage	±20	V
I _D	Drain Current	268	Α
	Continuous ($T_C = 25^{\circ}C$) (Note 5) Continuous ($T_C = 100^{\circ}C$) (Note 5)	190	
	Pulsed (Note 4)	1390	
E _{AS}	Single Pulsed Avalanche Energy (Note 3)	595	mJ
P _D	Power Dissipation	250	W
	$T_C = 25^{\circ}C$ $T_A = 25^{\circ}C$ (Note 1a)	3.8	
T _J , T _{STG}	Operating and Storage Temperature Range	-55 to +175	°C

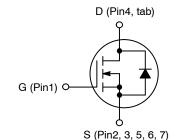
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



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V _{DS}	I _D MAX	r _{DS(on)} MAX
100 V	268 A	1.7 mΩ



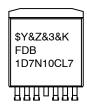
N-Channel MOSFET



- Gate
- Source Source
- . Drain 5. Source
- Source
- Source

D2PAK7 (TO-263 7 LD) CASE 418AY

MARKING DIAGRAM



\$Y = ON Semiconductor Logo 87 = Assembly Plant Code

= Numeric Date Code

= Lot Code FDB1D7N10CL7 = Specific Device Code

ORDERING INFORMATION

See detailed ordering and shipping information on page 3 of this data sheet.

THERMAL CHARACTERISTICS

Symbol	Parameter	Ratings	Unit
$R_{ hetaJC}$	Thermal Resistance, Junction to Case (Note 1)	0.6	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	40	

ELECTRICAL CHARACTERISTICS (T_{.I} = 25°C unless otherwise noted)

Symbol	Parameter	Test Cond	ditions	Min	Тур	Max	Unit
FF CHARACT	ERISTICS						
BV _{DSS}	Drain to Source Breakdown Voltage	$ID = 250 \mu A, VGS = 0 V$		100	_	_	V
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	ID = 250 μA, referenced to 25°C		-	57	-	mV/°C
I _{DSS}	Zero Gate Voltage Drain Current Zero Gate Voltage Drain Current	VDS = 80 V, VGS = 0) V	-	-	1	μΑ
I _{GSS}	Gate to Source Leakage Current	Vgs = ±20 V, Vps =	0 V	-	-	±100	nA
N CHARACTE	RISTICS						
V _{GS(th)}	Gate to Source Threshold Voltage	Vgs = Vps, Ip = 700) μΑ	2.0	3.1	4.0	V
$V_{GS(th)}/\Delta T_J$	Gate to Source Threshold Voltage Temperature Coefficient	ID = 700 μA, referen	nced to 25°C	-	-9	-	mV/°C
R _{DS(on)}	Static Drain to Source On Resistance	VGS = 10 V, ID = 10	0 A	-	1.5	1.75	mΩ
		VGS = 12 V, ID = 10	0 A	-	1.4	1.7	1
		VGS = 15 V, ID = 10	0 A	-	1.33	1.65	-
		VGS = 6 V, ID = 63 A	1	-	2.2	4.4	
		Vgs = 10 V, ID = 100 A, TJ= 150°C		-	2.65	3.1	
9 _{FS}	Forward Transconductance	VDS = 5 V, ID = 100 A		-	237	-	S
YNAMIC CHA	RACTERISTICS						
C _{iss}	Input Capacitance	VDS = 50 V, VGS = 0	Vps = 50 V, Vgs = 0 V, f = 1 MHz		8285	11600	pF
C _{oss}	Output Capacitance				5025	7035	pF
C _{rss}	Reverse Transfer Capacitance				50	80	pF
R _g	Gate Resistance			0.1	0.8	1.6	Ω
WITCHING CH	IARACTERISTICS	•					
t _{d(on)}	Turn-On Delay Time	V _{DD} = 50 V, I _D = 10	00 A,	_	39	63	ns
t _r	Rise Time	$V_{GS} = 10 \text{ V, R}_{GEN}$	= 6 12	_	33	53	ns
t _{d(off)}	Turn-Off Delay Time			_	85	136	ns
t _f	Fall Time			-	36	58	ns
Qg	Total Gate Charge	V _{GS} = 0 V to 10 V		-	116	163	nC
Qg	Total Gate Charge	V _{GS} = 0 V to 6 V		_	74	104	nC
Q _{gs}	Gate to Source Gate Charge		J ID = 100 A	_	37	-	nC
Q _{gd}	Gate to Drain "Miller" Charge			_	24	-	nC
Q _{oss}	Output Charge	VDD = 50 V, VGS = 0 V		-	333	-	nC
OURCE-DRAI	N DIODE CHARACTERISTICS						
I _S	Continuous Drain to Source Diode Forwa	rd Current		-	_	268	Α
I _{SM}	Pulsed Drain to Source Diode Forward C	urrent		-	-	1390	Α
V _{SD}	Source to Drain Diode Forward	Vgs = 0 V, Is = 100 A (Note 2)		_	0.9	1.2	V

ELECTRICAL CHARACTERISTICS (T_{.I} = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
SOURCE-DRAIN DIODE CHARACTERISTICS						
t _{rr}	Reverse Recovery Time	IF = 50 A, di/dt = 300 A/μs	-	63	101	ns
Q _{rr}	Reverse Recovery Charge		-	186	298	nC
t _{rr}	Reverse Recovery Time	IF = 50 A, di/dt = 1000 A/μs	-	82	132	ns
Q _{rr}	Reverse Recovery Charge		=	869	1390	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

- 1. R_{0JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design. a) 40°C/W when mounted on a 1 in2 pad of 2 oz copper.
 - b) 62.5 °C/W when mounted on a minimum pad of 2 oz copper.
- 2. Pulse Test: Pulse Width < 300 μs, Duty cycle < 2.0 %.
- 3. E_{AS} of 595 mJ is based on starting T_J = 25 °C, L = 0.3 mH, I_{AS} = 63 A, V_{DD} = 90 V, V_{GS} = 10 V. 100% test at L = 0.1 mH, I_{AS} = 91 A. 4. Pulsed Id please refer to Figure "Forward Bias Safe Operating Area" for more details.
- 5. Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

PACKAGE MARKING AND ORDERING INFORMATION

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDB1D7N10CL7	FDB1D7N10CL7	D2-PAK-7L	330 mm	24 mm	800 Units

TYPICAL CHARACTERISTICS

 $(T_J = 25^{\circ}C \text{ unless otherwise noted})$

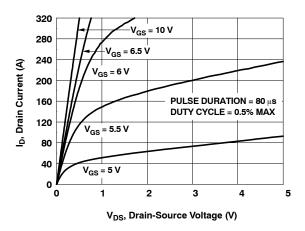


Figure 1. On-Region Characteristics

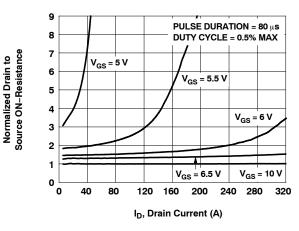


Figure 2. Normalized On-Resistance vs. Drain Current and Gate Voltage

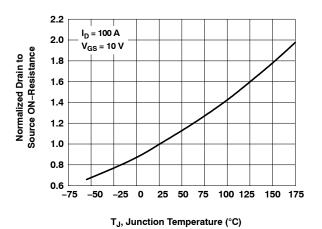


Figure 3. Normalized On–Resistance vs. Junction Temperature

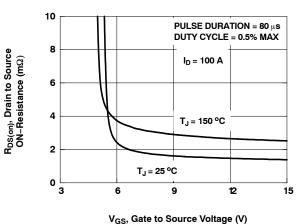


Figure 4. On-Resistance vs. Gate to Source Voltage

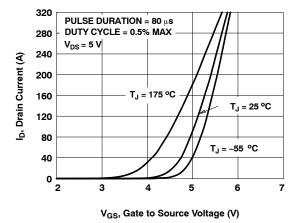


Figure 5. Transfer Characteristics

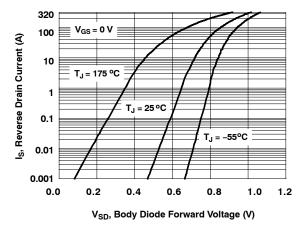


Figure 6. Source to Drain Diode Forward Voltage vs. Source Current

TYPICAL CHARACTERISTICS (Continued)

(T_J = 25°C unless otherwise noted)

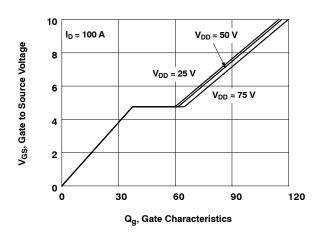


Figure 7. Gate Charge Characteristics

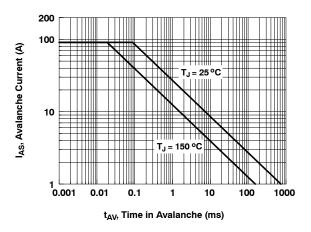


Figure 9. Unclamped Inductive Switching Capability

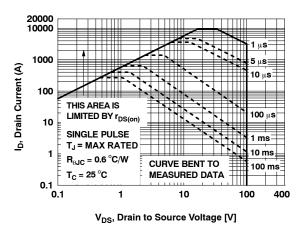
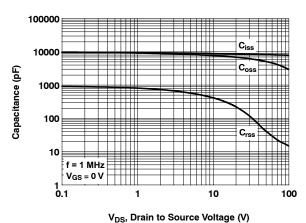


Figure 11. Forward Bias Safe Operating Area



v_{DS}, Drain to course voltage (v)

Figure 8. Capacitance vs. Drain to Source Voltage

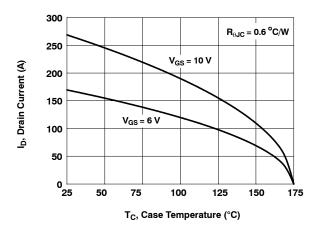


Figure 10. Maximum Continuous Drain Current vs. Case Temperature

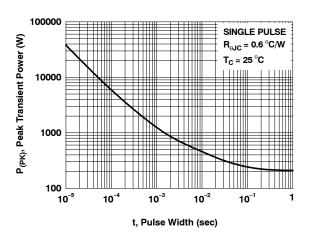


Figure 12. Single Pulse Maximum Power Dissipation

TYPICAL CHARACTERISTICS (Continued)

 $(T_J = 25^{\circ}C \text{ unless otherwise noted})$

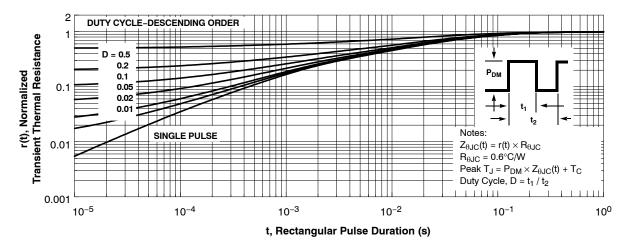
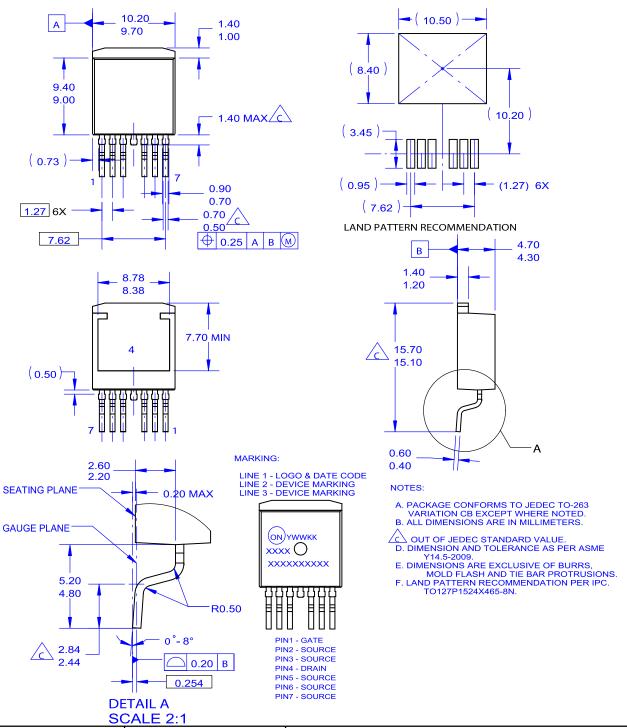


Figure 13. Normalized Max Junction to Case Transient Thermal Response Curve

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